

Timeway

LABORATORIES

Report No: EMC 0504081 File reference No: 2005-05-14

Applicant: Gembird Electronics Ltd.

Product: CPU and USB Manual Switch

Model No: CMSU-421

Trademark: Gembird

Test Standards: EN 55022:1998 EN 61000-3-2:2000

+A1:2000+A2:2003

EN 55024:1998 EN 61000-3-3:1995

+A1:2001+A2:2003 +A1:2001

Test result:

The EMC testing has been performed on the submitted samples

and found in compliance with council EMC Directive

89/336/EEC.

Approved By

Jack Chung

EMC Manager

Dated: March 14, 2005

Results appearing herein relate only to the sample tested

The technical reports is issued errors and omissions exempt and is subject to withdrawal at

HONG KONG TIMEWAY TECHNOLOGY DEVELOPMENT LIMITED

Rm.1805, 18/F., Wu Sang house, Nathan Road, Mongkok, Kln. HONG KONG

Tel (852) 2781 7498 Fax (852) 2381 2492





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1.0 General Details

1.1 Test Lab Details

Name: Hong Kong Timeway Technology Development Limited

Address: Rm.1805,18/F., Wu Sang House, Nathan Road, Mongkok, Kln. HONG KONG

Telephone: (852) 2781 7498 Fax: (852) 2381 2492

1.2 Applicant Details

Applicant: Gembird Electronics Ltd.

Address: Room 1709, New Building, #2 Shennan Zhong Lu, Shenzhen

Telephone: 86-755-82090225/82090379

Fax: 86-755-82090540

1.3 Description of EUT

Product: CPU and USB Manual Switch

Manufacturer: Gembird Electronics (Zhuhai) Co., Ltd.

Brand Name: Gembird
Model Number: CMSU-421

Additional Model Number: Additional Trade Name -

Rating: DC5V 350mA 1.75W

The Difference between models: -

1.4 Submitted Sample

1 Sample

1.5 Test Duration

2005-04-28 to 2005-05-14

1.6 Test Uncertainty

Conducted Emissions Uncertainty = ± 2.4 dB

Radiated Emissions Uncertainty = ± 4.2 dB

1.7 Test or witness Engineer

The sample tested by

Print Name: Ivy Zhu

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2.0 List of Measurement Equipment

2.1 Conducted Emission Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESCS30	830245/009	RS	2005.2.23	1Year
Coaxial Switch	MP59B	M70585	ANRITSU	N/A	N/A
ISN	NTFM8132	8132137	SCHWARZBECK	2005.2.24	1Year
ISN	NTFM8134	8134109	SCHWARZBECK	2005.2.24	1Year
ISN	NTFM8136	8136102	SCHWARZBECK	2005.2.24	1Year

2.2 Radiated Disturbance Test Equipment

				Calibration	Calibration
Name	Model No	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESCS30	830245/009	RS	2005.2.23	1Year
Coaxial Switch	MP59B	M70585	ANRITSU	N/A	N/A
Spectrum Analyzer(with	MS2661C	MT72089	ANRITSU	2005.2.23	
Tracking Generator)					1Year
Amplifier	MH648A	M20494	ANRITSU	2005.2.23	1Year
Bilog Antenna	CBL6101C	2576	CHASE	2005.2.23	1Year

2.3 Harmonic & Flicker Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Harmonics Flicker Test	5001ix-CTS				
System	-400	X71730	CI	2005.2.24	1Year

2.4 ESD Test Equipment

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
ESD Simulator	NSG435	2103	SCHNAFFNER	2005.2.23	1Year

2.5 Radiated electromagnetic disturbance test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESCS30	830245/009	RS	2005.2.23	1Year
Coaxial Switch	MP59B	M70585	ANRITSU	N/A	N/A

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Spectrum Analyzer(with		WAAAAA WAAAAA			
Tracking Generator)	MS2661C	MT72089	ANRITSU	2005.2.23	1Year
Amplifier	MH648A	M20494	ANRITSU	2005.2.24	1Year
Bilog Antenna	CBL6101C	2576	CHASE	2005.2.23	1Year

2.6 Electrical Fast Transient/Burst (EFT/B) immunity test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EFT Generator	NSG2025-1	2024	SCHNAFFNER	2005.2.23	1Year
Coupling Clamp	CDN126	418	SCHNAFFNER	N/A	N/A

2.7 Surge test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EMCPRO		9909302	KEYTEK	2005.2.23	1Year

2.8 Conducted Immunity test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
CW Generator	CW500	0399-10	EMTEST	2005.2.23	1Year
CDN	CDN-M2	9907105C	EMTEST	2005.2.23	1Year
CDN	CDN-M3	9905070C	EMTEST	2005.2.23	1Year
6dB Attenuator	ATT 6	9812105A	EMTEST	2005.2.23	1Year

2.9 Power Frequency magnetic field

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EMCPRO		9909302	KEYTEK	2005.2.23	1Year
Coil	F-1000-4-8/9/10-L-1M	9935	FCC	2005.2.23	1Year
Field Meter	ELF-66D	K71988-18	KEYTEK	2005.2.23	1Year

2.10 Voltage Dips/Interruptions immunity test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EMCPRO		9909302	KEYTEK	2005.2.23	1Year

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3.0 **Technical Details**

3.1 **Investigations Requested** Perform Electromagnetic Interference [EMI] & Electromagnetic Suspectability [EMS] tests for CE Marking

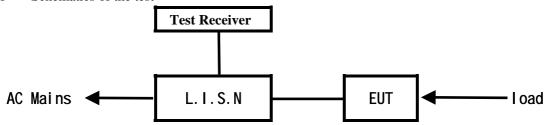
3.2 **Test Standards**

Test Standards					
	Limits and methods of measurement of radio disturbance				
EN 55022:1998	characteristics of in	formation technology equipment			
EN 33022:1998	Amendment A1:2000	to EN 55022:1998			
	Amendment A2:2003	to EN 55022:1998			
EN 61000-3-2:2000	Electromagnetic comp	patibility(EMC)- Part 3-2:Limits-Limits for harmonic			
EN 01000-3-2.2000	current emissions(equi	pment input current 16A per phase)			
	Electromagnetic comp	patibility (EMC)- Part 3-3:Limits-Limitation of voltage			
	changes, Voltage flu	changes, Voltage fluctuations and flicker in public low-voltage supply			
EN 61000-3-3:1995	systems. For equipment with rated current t 16A per phase and not				
	subject to conditional connection				
Amendment A1:2001 to EN 61000-3-3:1995					
	Electromagnetic Compatibility Generic Immunity Standard, Part				
EN 55024:1998	Residential, Commercial and Light Industry.				
21(33021.1))0	Amendment A1:2001 to EN 55024:1998				
	Amendment A2:2003	to EN 55024:1998			
	EN 61000-4-2:1995	Electrostatic discharge			
	EN 61000-4-3:1996 RF field strength susceptibility				
	EN 61000-4-4:1995 Electrical Fast transients				
	EN 61000-4-5:1995	95 Surge			
	EN 61000-4-6:1996	6 Conducted susceptibility			
	EN 61000-4-8:1994 Magnetic Field				
	EN 61000-4-11:1994	4 Dips/Voltage Interruption Variation			



4. Power line Conducted Emission Test

4.1 Schematics of the test

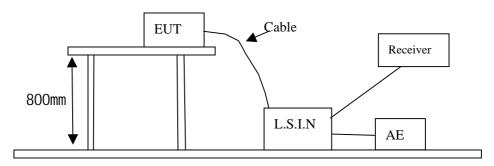


EUT: Equipment Under Test

4.2 Test Method:

The test was performed in accordance with EN 55022:1998

Block diagram of Test setup



4.3 Power line conducted Emission Limit

Eroguanay(MHz)	Limits dB(µ V)			
Frequency(MHz)	Quasi-peak Level	Average Level		
0.15 ~ 0.50	66.0 ~ 56.0*	56.0 ~ 46.0*		
0.50 ~ 5.00	56.0	46.0		
5.00 ~ 30.00	60.0	50.0		

Notes:

- 1. *decreasing linearly with logarithm of frequency.
- 2. The lower limit shall apply at the transition frequencies

4.4 Test Results

Limits for Conducted Emission test, Please refer to limit line (Quasi-peak) in the following diagram labelled as (QP)

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TEST REPORT

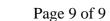
A Conducted Emission on Live Terminal of the power line (150kHz to 30MHz)

EUT set Condition: -

Results: N/A

Please refer to following diagram for individual

Eroguepey		Readi ng (dB µ V)			Li mi t	
Frequency (MHz)	Li ve	Live		Neutral		V)
(WITZ)	Quasi-peak	Average	Quasi-peak	Average	Quasi-peak	Average
			-	-		
			-	-		
			-	-		
			-	-		
			-	_		
			-	=		



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TEST REPORT

B Conducted Emission on Neutral Terminal of the power line (150kHz to 30MHz)

DITT		0	dition:	
EUL	set	Con	annon:	-

Results: N/A

Please refer to following diagram for individual

Eroguenev		Readi ng	(dB μ V)		Limit		
Frequency (MHz)	Li ve)	Neutral		(dB µ V)		
(WITZ)	Quasi-peak	Average	Quasi-peak	Average	Quasi-peak	Average	
	-	-					
	-	-					
	-	-					
	-	-					
	-	-					
	_	_					



5 Radiated Disturbance Test

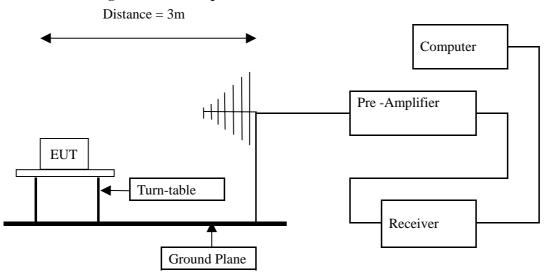
5.1 Schematics of the test



5.2 Test Method:

The test was performed in accordance with EN 55022:1998

Block diagram of Test setup



5.3 Power line conducted Emission Limit

Frequency Range(MHz)	Peak limits (dB µ V/m)
30-230	40.0
230-1000	47.0

Note: The lower limit shall apply at the transition frequencies

5.4 Test result

Please refer to following table

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Radiated Disturbance In Horizontal (30MHz----1000MHz)

EUT set Condition: Normal Operation Mode

Results: Pass

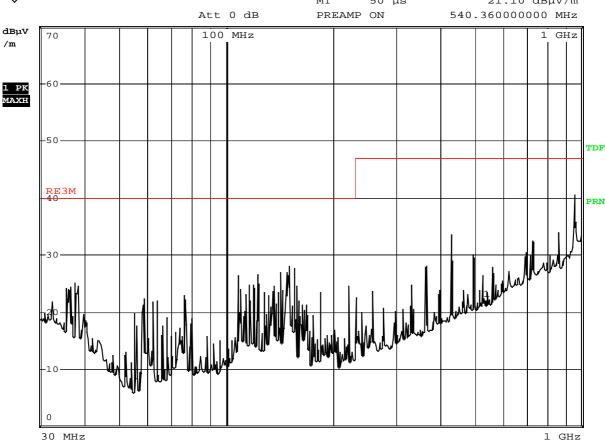
Please refer to following diagram for individual

/m

RBW 120 kHz Marker 1 [T1] $21.10 \ dB\mu V/m$ MT50 µs

Att 0 dB PREAMP ON



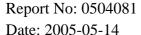


Date: 9.MAY.2005 17:29:27

Frequency (MHz)	Level@3m (dB μ V/m)	Antenna Polarity	Limit@3m (dB \(\mu\) V/m)
60.002	28.92	Н	40
76.261	16.18	Н	40
108.001	26.94	Н	40
432.087	33.85	Н	47
960.197	38.38	Н	47

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Radiated Disturbance In Vertical (30MHz----1000MHz)

EUT set Condition: Normal Operation Mode

Results: Pass

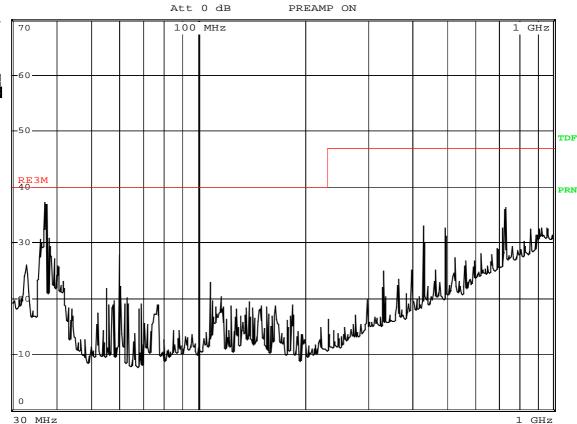
Please refer to following diagram for individual

dBuV

120 kHz RBW МТ 50 µs

PREAMP ON





Date: 9.MAY.2005 17:42:36

Frequency (MHz)	Level@3m (dB μ V/m)	Antenna Polarity	Limit@3m (dB µ V/m)
36.867	36.31	V	40
37.823	27.61	V	40
60.001	29.40	V	40
108.229	17.10	V	40
432.088	35.42	V	47

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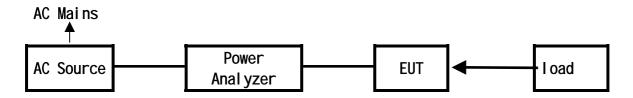
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6. Voltage Fluctuations & Flicker Test

6.1 Schematic of the test



EUT: Equipment Under Test

6.2 Test Method:

The test was performed in accordance with EN 61000-3-3:1995

6.3 Test Results

Result: N/A

* N/A --- The test is not applicable for the product because the power less than 70W.

Please refer to the following pages

Maximum Occurring Levels:

Ut: 230.1 (EUT Test RMS Voltage)

Pst:	Limit=	1.0	(The Highest short Term Flicker Value)
Plt:	Limit=	0.65	(The Highest Long Term Flicker Value)
dt(%):	Limit=	4%	(The Highest instantaneous Voltage Change (10ms))
dc(%):	Limit=	3%	(The highest Relative steady state voltage change (1sec))
dmax:	Limit=	4%	(The highest Max Relative voltage change)
Tdt:	Limit=	200ms	(The Max Time(in milli-sec) that dt exceeds 3%)

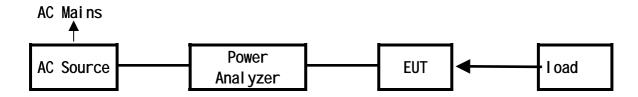
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7.0 Harmonic Current Emission Test

7.1 Schematic of the test



EUT: Equipment Under Test

7.2 Test Method

The test was performed in accordance with EN 61000-3-2: 2000

*: The Level of the product is : CLASS A

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7.3 **Test Results**

Result:N/A

* N/A --- The test is not applicable for the product because the power less than 70W. Please refer to the following pages

Rating:

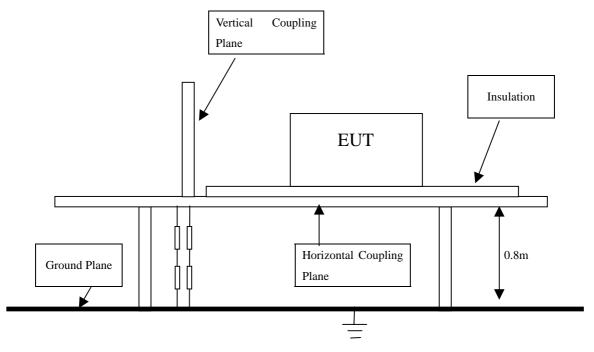
Harmonic results as a% of the limits

No	(Test	No	(Test	No	(Test	No	(Test
	result/Limit)%		result/Limit)%		result/Limit)%		result/Limit)%
1		10		21		31	
2		12		22		32	
3		13		23		33	
4		14		24		34	
5		15		25		35	
6		16		25		36	
7		17		27		37	
8		18		28		38	
9		19		29		39	
10		20		30		40	



8.0 Electrostatic Discharge

8.1 Schematic of the test



8.2 Test method

The test was performed in accordance with EN 61000-4-2:1995

8.3 Test severity

- ± 4kV for direct & in-direct Contact Discharge
- ± 8kV for air Discharge

Performance Criterion Require: B (Please see following table)

8.4 Susceptibility performance Criteria and Severity level

A	Normal performance within the specification limits
В	Temporary degradation or loss of function or performance which is
	self recoverable
С	Temporary degradation or loss of function or performance which
	requires operator intervention or system reset
D	Degradation or loss of function which is not recoverable due to
	damage of equipment(components) or software, or loss of data

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Severity Level

Level	Test Voltage Direct & in-direct contact	Test Voltage Air
	Discharge (kV)	discharge(kV)
1	± 2kV	± 2kV
2	±4kV	± 4kV
3	± 6kV	± 8kV
4	±8kV	± 15kV

8.5 Test Result

Please refer to the following table for individual results.

Location	Discharge Method	Test Voltage	Results
HCP (Horizontal coupling plane)	Contact Discharge	±4kV	PASS
VCP(Vertical Coupling plane)	Contact Discharge	±4kV	PASS
Cover	Contact Discharge	±4kV	PASS
PCI Signal Terminals	Contact Discharge	±4kV	PASS
Mouse Terminals	Contact Discharge	±4kV	PASS
Keyboard Terminals	Contact Discharge	±4kV	PASS
USB	Contact Discharge	±4kV	PASS
PC2 all the terminals	Contact Discharge	±4kV	PASS
PC3 all the terminals	Contact Discharge	±4kV	PASS
PC4 all the terminals	Contact Discharge	±4kV	PASS
Console Mouse terminals	Contact Discharge	±4kV	PASS
Keyboard terminals	Contact Discharge	±4kV	PASS
Switch	Contact Discharge	±4kV	PASS
Location	Discharge Method	Test Voltage	Results
HCP (Horizontal coupling plane)	Air Discharge	±8kV	PASS
VCP(Vertical Coupling plane)	Air Discharge	±8kV	PASS
Cover	Air Discharge	±8kV	PASS
PCI Signal Terminals	Air Discharge	±8kV	PASS
Mouse Terminals	Air Discharge	±8kV	PASS
Keyboard Terminals	Air Discharge	±8kV	PASS
USB	Air Discharge	±8kV	PASS
PC2 all the terminals	Air Discharge	±8kV	PASS
PC3 all the terminals	Air Discharge	±8kV	PASS
PC4 all the terminals	Air Discharge	±8kV	PASS
Console Mouse terminals	Air Discharge	±8kV	PASS
Keyboard terminals	Air Discharge	±8kV	PASS

Remark: Calculated measurement uncertainty= ±0.2kV

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9.0 RF field strength susceptibility (80MHz----- 1000MHz)

9.1 Schematics of the test



9.2 Test Method:

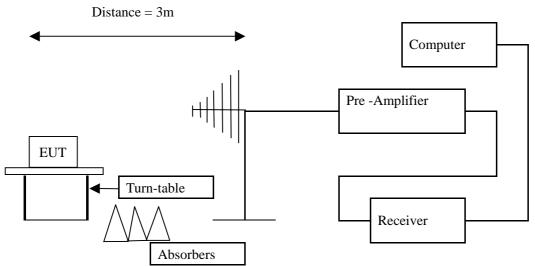
The test was performed in accordance with EN 61000-4-3:1996

Severity: Level 2 (3V/m)

Modulation: 80% AM

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



9.3 Susceptibility performance Criteria and severity Level

Susceptibility performance Criteria

busceptionity performan	ice criteria
A	Normal performance within the specification limits
В	Temporary degradation or loss of function or performance which is
	self recoverable
С	Temporary degradation or loss of function or performance which
	requires operator intervention or system reset
D	Degradation or loss of function which is not recoverable due to
	damage of equipment(components) or software, or loss of data

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Severity Level

Level	Field Strength (V/m)
1	1
2	3
3	10

9.4 Test Result:

Please refer to the following table for individual results.

Frequency (MHz)	Face	Polarity	Level (V/m)	Dwell Time(s)	Sweep Rate (%)	Results
80-1000	0°	Horizontal	3	1	1	PASS
80-1000	90 °	Horizontal	3	1	1	PASS
80-1000	180 °	Horizontal	3	1	1	PASS
80-1000	270 °	Horizontal	3	1	1	PASS
80-1000	0°	Vertical	3	1	1	PASS
80-1000	90 °	Vertical	3	1	1	PASS
80-1000	180 °	Vertical	3	1	1	PASS
80-1000	270 °	Vertical	3	1	1	PASS

Remark: Calculated measurement uncertainty= 80MHz to 1000mHz (+3.7/ -1.3) V/m

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10.0 Electrical Fast Transient/Burst (EFT/B) immunity test

10.1 Schematics of the test



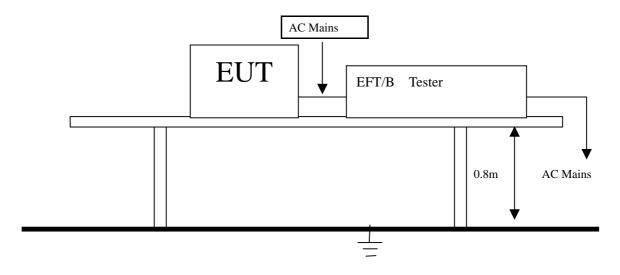
10.2 Test Method:

The test was performed in accordance with EN 61000-4-4:1995

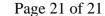
Severity: Level 2 (1kV)

Performance Criterion Require: B (Please see following table)

Block diagram of Test setup



10.3 Susceptibility performance Criteria and Severity Level Susceptibility performance Criteria





A	Normal performance within the specification limits
В	Temporary degradation or loss of function or performance which is
	self recoverable
С	Temporary degradation or loss of function or performance which
	requires operator intervention or system reset
D	Degradation or loss of function which is not recoverable due to
	damage of equipment(components) or software, or loss of data

Severity Level

	Open Circuit output Test Voltag	ge ± 10%
Level	On power Supply Lines	On I/O (Input/output) Signal data and control lines
1	0.5kV	0.5kV
2	1kV	1kV
3	2kV	2kV
4	4kV	4kV
X	Special	Special

10.4 Test Results

Please refer to following page.

Inject location:

Inject Line	Voltage	Inject	Method	Results
	kV	Times (s)		
L	±1	120S	Direct	PASS
N	± 1	120S	Direct	PASS
L-N	± 1	120S	Direct	PASS

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11.0 Surge test

11.1 Schematics of the test



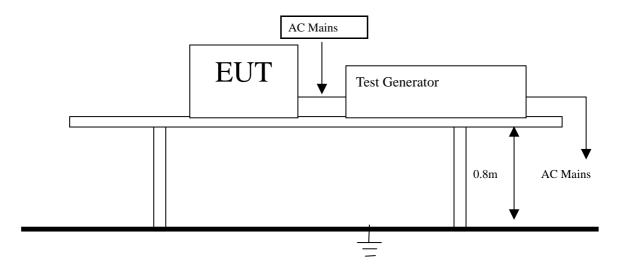
11.2 Test Method:

The test was performed in accordance with EN 61000-4-5:1995

Severity: Level 2 (Line to Neutral at 1kV)

Performance Criterion Require: C (Please see following table)

Block diagram of Test setup



11.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

A	Normal performance within the specification limits
В	Temporary degradation or loss of function or performance which is
	self recoverable
С	Temporary degradation or loss of function or performance which
	requires operator intervention or system reset
D	Degradation or loss of function which is not recoverable due to
	damage of equipment(components) or software, or loss of data

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Severity Level

Severity Level	Open-Circuit Test Voltage		
	kV		
1	0.5		
2	1.0		
3	2.0		
4	4.0		
*	Special		

11.4 Test Results

Please refer to following page.

Test location:

Location	Polarity	Phase	No of	Pulse	Results
		Angle	Pulse	Voltage(kV)	
L-N	+	0	5	1.0	PASS
	+	90	5	1.0	PASS
	+	180	5	1.0	PASS
	+	270	5	1.0	PASS
	-	0	5	1.0	PASS
	-	90	5	1.0	PASS
	-	180	5	1.0	PASS
	-	270	5	1.0	PASS

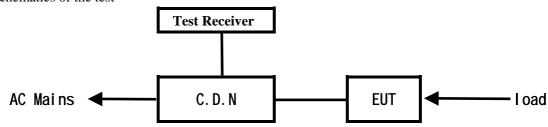
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12.0 Conducted Immunity test

12.1 Schematics of the test



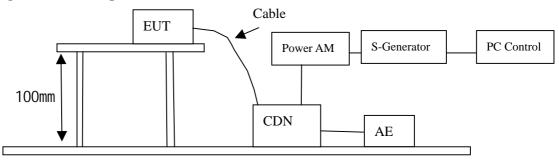
12.2 Test Method

The test was performed in accordance with EN 61000-4-6:1996

Severity: Level 2 (3 V rms),0.15MHz—80MHz

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



12.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

A	Normal performance within the specification limits
В	Temporary degradation or loss of function or performance which is
	self recoverable
С	Temporary degradation or loss of function or performance which
	requires operator intervention or system reset
D	Degradation or loss of function which is not recoverable due to
	damage of equipment(components) or software, or loss of data

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Severity Level

Severity Level	Field Strength V/m		
1	1		
2	3		
3	10		
*	Special		

12.4 Test Results:

Please refer to the following page

The most relief to the Tollowing Page				
Frequency	Injected Position	Strength	Criterion	Result
Range (MHz)				
0.15 - 20	AC Line	3V (rms)	٨	PASS
		Unmodulated	A	
20 - 80	AC Line	3V (rms)	Δ.	PASS
		Unmodulated	A	

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13.0 Power Frequency magnetic field test

13.1 Schematics of the test



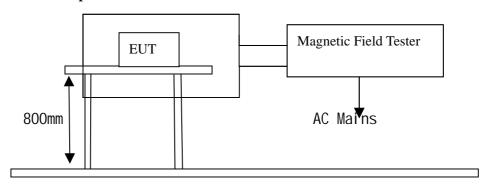
13.2 Test Method

The test was performed in accordance with EN 61000-4-8:1993

Severity: Level 2 (3A/m),

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



13.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

A	Normal performance within the specification limits
В	Temporary degradation or loss of function or performance which is self recoverable
	Sen recoverable
C	Temporary degradation or loss of function or performance which
	requires operator intervention or system reset
D	Degradation or loss of function which is not recoverable due to
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Severity Level

Severity Level	Magnetic Field Strength A/m			
1	1			
2	3			
3	10			
4	30			
5	100			
*	Special			

13.4 Test Results:

Please refer to the following page

Test Level	Testing Duration	Coil Orientation	Criterion	Result
3A/m	5 Mins	Horizontal	A	PASS
3A/m	5 Mins	Vertical	A	PASS

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14.0 Voltage Dips/Interruptions immunity test

14.1 Schematics of the test

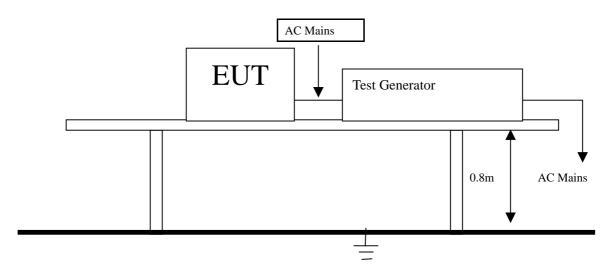


14.2 Test Method:

The test was performed in accordance with EN 61000-4-11:1994

Performance Criterion Require: C&B (Please see following table)

Block diagram of Test setup



14.3 Susceptibility performance Criteria and Severity Level Susceptibility performance Criteria

A	Normal performance within the specification limits
В	Temporary degradation or loss of function or performance which is
	self recoverable
С	Temporary degradation or loss of function or performance which
	requires operator intervention or system reset
D	Degradation or loss of function which is not recoverable due to
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Severity Level

Test Level %Ut	Voltage dip and short interruptions %Ut	Duration(in period)
0	100	0.5
	100	1
40	60	5
		10
70	30	25
		50
		*

14.4 Test Result:

Please refer to the following page

Test Level	Voltage	Duration(in	Phase Angle	Criterion	Result
% Ut	dips &short	period)			
	interruptions				
	% Ut				
0	100	250P	0 ° - 360 °	С	PASS
40	60	5P	0 ° - 360 °	С	PASS
70	30	0.5P	0 ° - 360 °	В	PASS

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15.0 Product Labeling

15.1 CE Mark label specification

Text of the mark is black or white in color and is left justified. Labels are printed in indelible ink on permanent adhesive backing and shall be affixed at a conspicuous location on the EUT or silk-screened onto the EUT.



15.2 Mark Location: Rear enclosure

*

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Appendix:

Photos of the Product



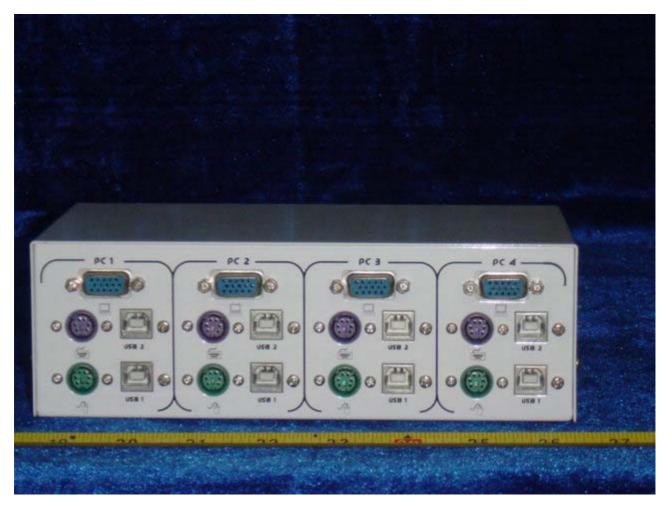
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Appendix:

Photos of the Product



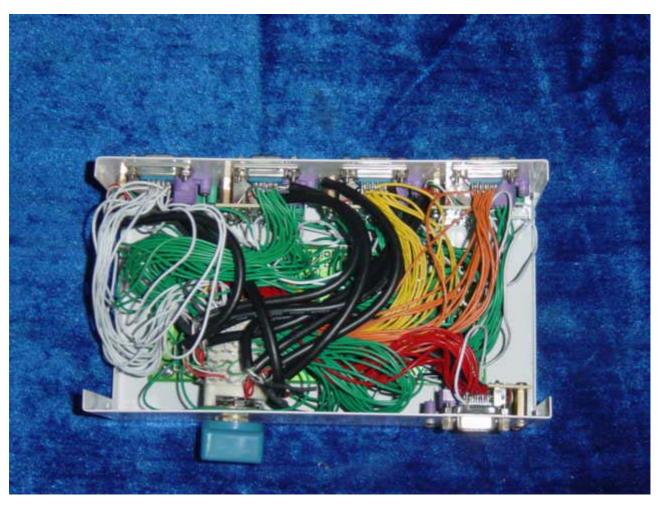
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Appendix:

Photos of the Product



End of the report